

## Discussion

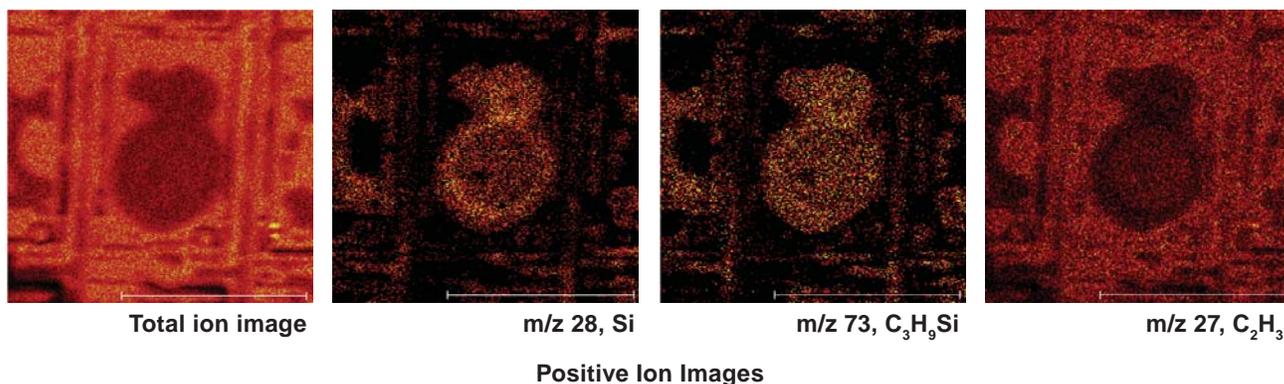
The manufacture of modern flat panel displays involves the use of advanced high technology processes and materials. Production of TFT-LCDs (Thin film transistor liquid crystal displays) involves the merging of traditional Si semiconductor processing technology with glass processing and fine chemicals.

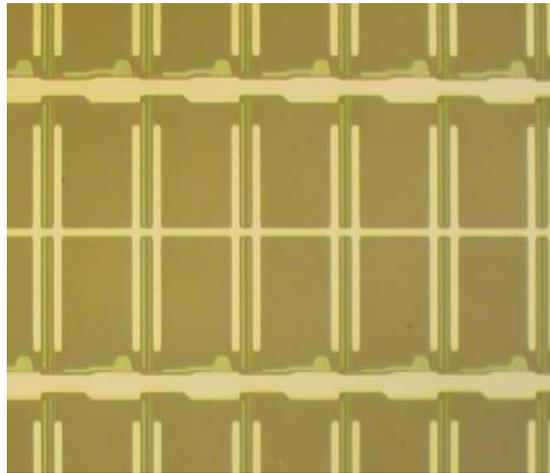
This application note focuses on the use of TOF-SIMS (Time-of-Flight Secondary Ion Mass Spectrometry) for the analysis of residue formed during a TFT manufacturing step. TOF-SIMS provides highly specific chemical information (both atomic and molecular) from the top 10-30Å of a surface.

In this case, circular defects filling almost whole cells were found to be present during inspection of the display. A typical area of the TFT structure is shown on page 2. Each cell is about 100µm wide. The defects were only visible when liquid crystals were present within the structure and the defect positions were noted at that point. The defects were suspected to be organic in nature.

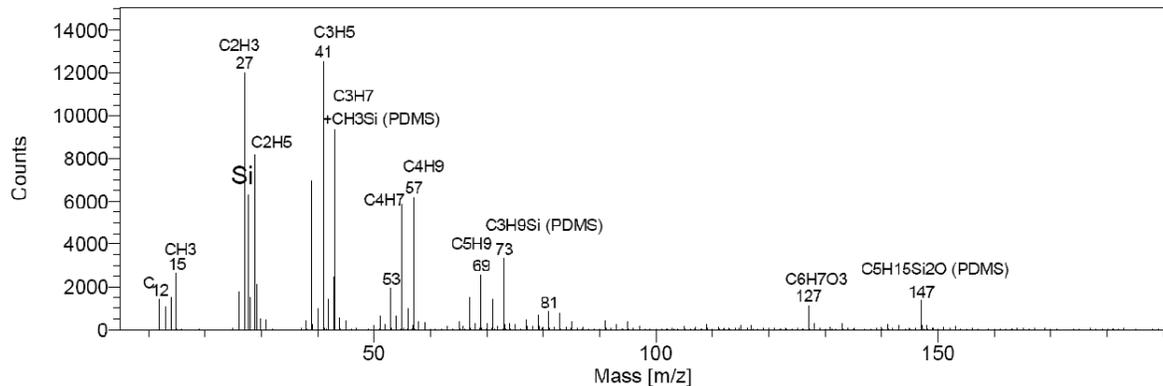
TOF-SIMS data can be displayed as either ion images or as mass spectra. The images below show the lateral distribution of selected species on a TFT surface. Mass spectra show the specific molecular and atomic species present in a particular region within the image, in this case from the defect.

Shown below are the total ion image (all positive ions from the sample), and also positive ion images for Si, C<sub>3</sub>H<sub>9</sub>Si and C<sub>2</sub>H<sub>3</sub>. The defect is the dark circular area in the middle of the total ion image. The Si and C<sub>3</sub>H<sub>9</sub>Si map with the defect whereas other organic ions (e.g. C<sub>2</sub>H<sub>3</sub>) do not. C<sub>3</sub>H<sub>9</sub>Si and other ions marked in the mass spectrum are due to PDMS (polydimethylsiloxane). PDMS is widely used in industrial materials, as a polish, mold release agent, lubricant, pump oil and also as a component in some adhesives. Page 2 shows a positive ion mass spectrum of the defect. In this failure analysis example, the PDMS was traced to a specific source within the manufacturing process. This example illustrates the important and useful information that can be obtained using the correct analytical instrumentation to address a manufacturing problem in the FPD industry.





Optical image of analytical area of interest



Positive Ion TOF-SIMS Spectrum of a Defect on a Flat Panel Display

**United States Locations**

Tempe, Arizona  
 +1 480 239 0602 info.az@eaglabs.com  
 +1 602 470 2655 fax

Sunnyvale, California  
 810 Kifer Road  
 +1 408 530 3500 info.ca@eaglabs.com  
 +1 408 530 3501 fax

1135 E Arques Avenue  
 +1 408 738 3033  
 +1 408 530 3035 fax

785 Lucerne Drive  
 +1 408 737 3892  
 +1 408 737 3916 fax

Peabody, Massachusetts  
 +1 978 278 9500 info.ma@eaglabs.com  
 +1 978 278 9501 fax

Chanhassen, Minnesota  
 +1 952 828 6411 info.mn@eaglabs.com  
 +1 952 828 6449 fax

East Windsor, New Jersey  
 +1 609 371 4800 info.nj@eaglabs.com  
 +1 609 371 5666 fax

Syracuse, New York  
 +1 315 431 9900 info.ny@eaglabs.com  
 +1 315 431 9800 fax

Raleigh, North Carolina  
 +1 919 829 7041 info.nc@eaglabs.com  
 +1 919 829 5518 fax

Round Rock, Texas  
 +1 512 671 9500 info.tx@eaglabs.com  
 +1 512 671 9501 fax

**International Locations**

Shanghai, China  
 + 86 21 6879 6088 info.cn@eaglabs.com  
 + 86 21 6879 9086 fax

Tournefeuille, France  
 + 33 5 61 73 15 29 info.fr@eaglabs.com  
 + 33 5 61 73 15 67 fax

Frankfurt, Germany  
 + 49 (0) 693053213 info.de@eaglabs.com  
 + 49 (0) 69307941 fax

Tokyo, Japan  
 + 81 3 5396 0531 info.jp@eaglabs.com  
 + 81 3 5396 1930 fax

HsinChu, Taiwan  
 + 886 3 5632303 info.tw@eaglabs.com  
 + 886 3 5632306 fax

Uxbridge, United Kingdom  
 + 44 (0) 1895 811194 info.uk@eaglabs.com  
 + 44 (0) 1895 810350 fax